

Notice of References CitedApplication/Case No.
09/977,994Applicant(s)/Patent Under
Reexamination
NAGATA ET AL.Examiner
Jeffrey R. WestArt Unit
2857

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.